

Notice of References Cited	Application/Control No. 09/782,106	Applicant(s)/Patent Under Reexamination BOIS ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,973,174	11-1990	Losic et al.	388/811
	B	US-6,137,293	10-2000	Wu et al.	324/638
	C	US-5,365,179	11-1994	Rogers, Wesley A.	324/650
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Qingjian Yu; Wing, O.; "Computational models of transmission lines with skin effects and dielectric loss"; Circuits and Systems I: Fundamental Theory and Applications, IEEE Transactions on , Vol 41 , Issue: 2, Feb. 1994; Pgs 107 - 119				
	V	Yungseon Eo; Eisenstadt, W.R.; Jongin Shim; "S-parameter-measurement-based high-speed signal transient characterization of VLSI interconnects on SiO ₂ -Si substrate"; Advanced Packaging, IEEE Transactions on, Vol 23 , Iss 3 , Aug. 2000; Pgs 470 - 479				
	W	Gordon, C.; Blazeck, T.; Mittra, R.; "Time-domain simulation of multiconductor transmission lines with frequency-dependent losses"; Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Vol 11 , Iss 11 , Nov. 1992; Pgs:1372 -1387				
	X	Bois, K.J.; Handjojo, L.F.; Benally, A.D.; Mubarak, K.; Zoughi, R.; "Dielectric plug-loaded two-port transmission line measurement technique for dielectric property characterization of granular and liquid materials"; IEEE Vol 48, Iss 6, Dec. 1999				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	A	US-			
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	I	US-			
	J	US-			
	K	US-			
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Veijola, T.; Valtonen, M.; "Dispersive transmission line model for nonlinear time domain circuit analysis"; Circuits and Systems, 1988, IEEE International Symposium on , 7-9 Jun 1988 Pgs:2839 - 2842 vol.3□□
	V	Janezic, M.D.; Jargon, J.A.; "Complex permittivity determination from propagation constant measurements" Microwave and Guided Wave Letters, IEEE [see also IEEE Microwave and Wireless Components Letters] , Volume: 9 , Issue: 2 , Feb. 1999 ;Pages:76 - 78□□
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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